



<b>Search Notes</b>  	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10058781	KAKIZAKI ET AL.
	Examiner Kim, David S	Art Unit 2633

Notes	Date	Examiner
EAST search - see search history printout	3/30/2006	DSK, 3/31/06, 4/3/06
www.google.com - various combinations of the following terms: monitor detect optical switch reflections	4/3/2006	DSK
scholar.google.com - various combinations of the following terms: monitor detect optical switch reflections	4/3/2006	DSK
ieeexplore.ieee.org - various combinations of the following terms: optic* photon* switch monitor* local* detect* reflect* deflect*	4/3/2006	DSK
text search in 359/196-226	4/3/2006	DSK
consulted with Examiner Mohammad Sedighian allowability of claim 11	4/3/2006	DSK
consulted with SPE Jason Chan about the allowability of claims 5-6	4/3/2006	DSK
U.S. Patent and Trademark Office		Part of Paper No.: 03292006

<p><b>Searched</b></p> 	<p>Application/Control No.</p> <p>10058781</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>KAKIZAKI ET AL.</p>
	<p>Examiner</p> <p>Kim, David S</p>	<p>Art Unit</p> <p>2633</p>

Class	Sub Class	Date	Examiner
398	12, 19	3/30/2006	DSK

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